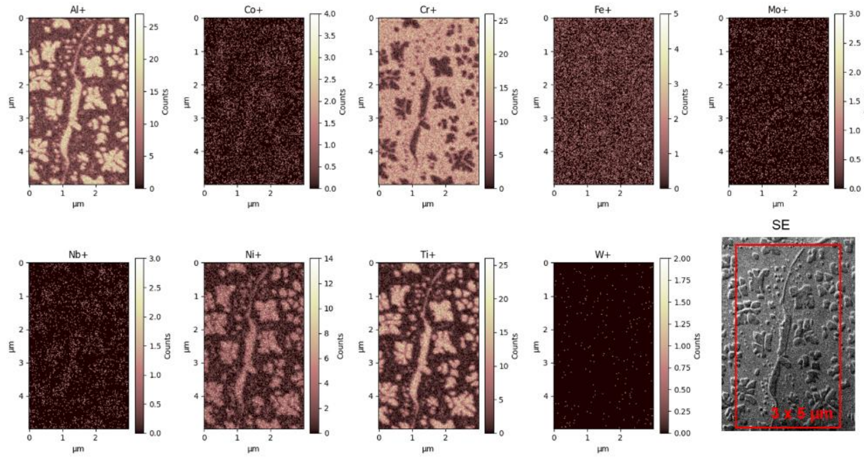

Fig. 1: Elemental maps obtained by O-TOFSIMS in the FIB/SEM UHV workstation on γ-γ' Ni based superalloy, revealing that the very fine (few tens of nm) precipitates are indeed consistent with γ'-Ni3(Al, Ti). FIB conditions were 30kV, 1pA and 50µs of pixel time. The total time of this FIB/SIMS analysis was 30 seconds. At bottom on the right the secondary electron image show in the red square the localization of the SIMS analyse.